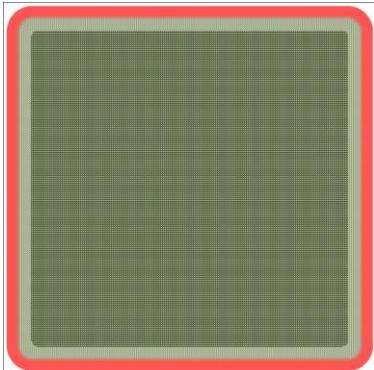


**SiC Silicon-Carbide**

**1200V 20A Schottky Diode**

<b>Bonding Pad Information</b>		<b>Chip Information</b>	
		Die Size (With Scribe Line)	3,048µm x 3,048µm
		Anode Pad Size	2,498µm x 2,498µm
		Scribe Line Size	100µm
		Wafer Size	6inches
		Wafer Thickness	180µm
		Gross Die	1,657ea
		Metallization	Front Side : Al/Cu : 4.0µm
			Back Side : Ti/Ni/Ag : 2.0µm

**Maximum Ratings (T<sub>c</sub>=25°C unless otherwise noted)**

Parameter	Symbol	Value	Unit
Repetitive Peak Reverse Voltage	V <sub>RRM</sub>	1200	V
Surge Peak Reverse Voltage	V <sub>RSM</sub>	1200	V
DC Current	I <sub>F</sub>	20	A
Operating Junction and Storage Temperature Range	T <sub>J</sub>	-55 to 175	°C

**Electrical Characteristics (T<sub>A</sub>=25°C unless otherwise noted)**

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
DC Blocking Voltage	V <sub>R</sub>	I <sub>R</sub> =100uA	1200	-	-	V
Forward Voltage	V <sub>F</sub>	I <sub>F</sub> =10A, T <sub>J</sub> =25°C	-	1.2	1.5	V
		I <sub>F</sub> =10A, T <sub>J</sub> =175°C	-	1.5	-	
		I <sub>F</sub> =20A, T <sub>J</sub> =25°C	-	1.5	1.8	
		I <sub>F</sub> =20A, T <sub>J</sub> =175°C	-	2.2	-	
Reverse Current	I <sub>R</sub>	V <sub>R</sub> =1200V, T <sub>J</sub> =25°C	-	3	50	µA
		V <sub>R</sub> =1200V, T <sub>J</sub> =175°C	-	50	600	
Total Capacitive Charge	Q <sub>C</sub>	V <sub>R</sub> =800V, T <sub>J</sub> =25°C $Q_C = \int_0^{V_R} C(V) dV$	-	94	-	nC
Total Capacitance	C <sub>j</sub>	V <sub>R</sub> =800V, f=1MHz	-	76	-	pF

**NOTE:**

- I<sub>F</sub> evaluated by TO247-2L package type.
- The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.